

### BUZ80 BUZ80FI

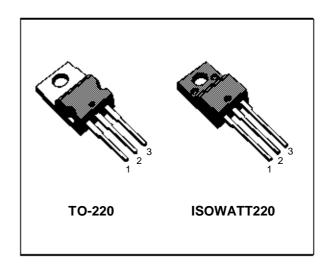
# N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR

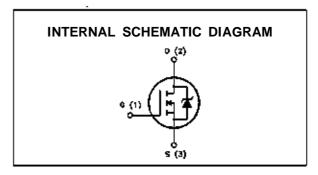
TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	ΙD
BUZ80	800 V	< 4 Ω	3.4 A
BUZ80FI	800 V	< 4 Ω	2.1 A

- TYPICAL  $R_{DS(on)} = 3.3 \Omega$
- AVALANCHE RUGGEDNESS TECHNOLOGY
- 100% AVALANCHE TESTED
- REPETITIVE AVALANCHE DATA AT 100°C
- LOW INPUT CAPACITANCE
- LOW GATE CHARGE
- APPLICATION ORIENTED CHARACTERIZATION

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- CONSUMER AND INDUSTRIAL LIGHTING
- DC-AC INVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLY (UPS)





#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Val	Unit	
		BUZ80	BUZ80FI	
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	80	00	V
$V_{DGR}$	Drain- gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	80	00	V
Vgs	Gate-source Voltage	± :	20	V
$I_{D}$	Drain Current (continuous) at T <sub>c</sub> = 25 °C	3.4	2.1	А
$I_{D}$	Drain Current (continuous) at T <sub>c</sub> = 100 °C	2.1	1.3	А
I <sub>DM</sub> (•)	Drain Current (pulsed)	13	13	А
P <sub>tot</sub>	Total Dissipation at T <sub>c</sub> = 25 °C	100	40	W
	Derating Factor	0.8	0.32	W/°C
V <sub>ISO</sub>	Insulation Withstand Voltage (DC)			V
T <sub>stg</sub>	Storage Temperature	-65 to	°C	
Tj	Max. Operating Junction Temperature	15	50	°C

<sup>(•)</sup> Pulse width limited by safe operating area

April 1993 1/10

#### THERMAL DATA

			TO-220	ISOWATT220	
R <sub>thj-case</sub>	Thermal Resistance Junction-case	Max	1.25	3.12	°C/W
R <sub>thj-amb</sub> R <sub>thc-sink</sub> T <sub>I</sub>	Thermal Resistance Junction-ambient Thermal Resistance Case-sink Maximum Lead Temperature For Soldering P	Max Typ urpose	62 0. 30	5	°C/W °C/W °C

#### **AVALANCHE CHARACTERISTICS**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max, $\delta$ < 1%)	3.4	А
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	180	mJ
E <sub>AR</sub>	Repetitive Avalanche Energy (pulse width limited by $T_j$ max, $\delta$ < 1%)	4.8	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (T <sub>c</sub> = 100 °C, pulse width limited by T <sub>i</sub> max, δ < 1%)	2.1	А

## **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25$ $^{o}C$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \mu\text{A}$ $V_{GS} = 0$	800			٧
		$V_{DS} = Max Rating$ $V_{DS} = Max Rating x 0.8 T_c = 125 °C$			250 1000	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			± 100	nA

#### ON (\*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 1 \text{ mA}$	2	3	4	V
RDS(on)	Static Drain-source On Resistance	$V_{GS} = 10 \text{ V}$ $I_{D} = 1.7 \text{ A}$ $V_{GS} = 10 \text{ V}$ $I_{D} = 1.7 \text{ A}$ $T_{c} = 100^{\circ}\text{C}$		3.3	4 8	$\Omega$
I <sub>D(on)</sub>	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	3.4			А

#### **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_{D} = 1.7 \text{ A}$	1	3.5		S
	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25 V f = 1 MHz V <sub>GS</sub> = 0		650 82 28	850 105 40	pF pF pF



#### **ELECTRICAL CHARACTERISTICS** (continued)

#### **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Time Rise Time	$V_{DD} = 30 \text{ V}$ $I_D = 2.1 \text{ A}$ $R_G = 50 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 3)			50 110	ns ns
(di/dt) <sub>on</sub>	Turn-on Current Slope	$V_{DD} = 640 \text{ V}$ $I_D = 3 \text{ A}$ $R_G = 50 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 5)		170		A/μs
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 400 \text{ V}$ $I_D = 3 \text{ A}$ $V_{GS} = 10 \text{ V}$		42 6 17	55	nC nC nC

#### **SWITCHING OFF**

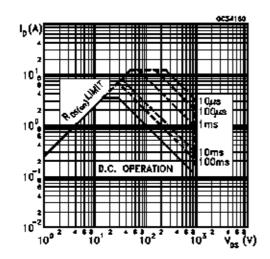
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
` ′	, ,	$V_{DD} = 640 \text{ V}  I_{D} = 3 \text{ A}$		95	120	ns
tf	Fall Time	$R_G = 50 \Omega$ $V_{GS} = 10 V$		20	25	ns
t <sub>c</sub>	Cross-over Time	(see test circuit, figure 5)		120	165	ns

#### SOURCE DRAIN DIODE

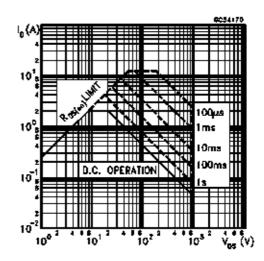
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)				3.4 13	A A
Vsp (*)	Forward On Voltage	IsD = 6 A VGS = 0			2.5	٧
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 3 \text{ A}$		700		ns
Q <sub>rr</sub>	Reverse Recovery Charge	(see test circuit, figure 5)		8.8		μC
I <sub>RRM</sub>	Reverse Recovery Current			25		А

<sup>(\*)</sup> Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

#### Safe Operating Areas For TO-220

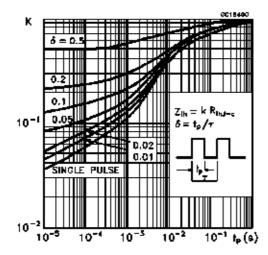


#### Safe Operating Areas For ISOWATT220

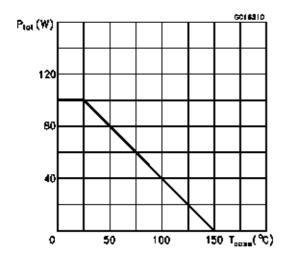


<sup>(•)</sup> Pulse width limited by safe operating area

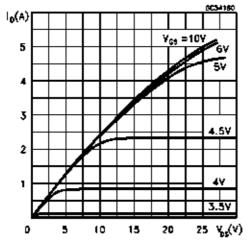
Thermal Impedeance For TO-220



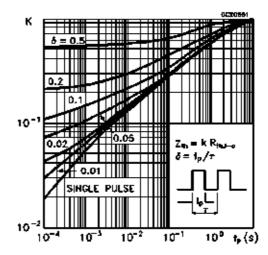
Derating Curve For TO-220



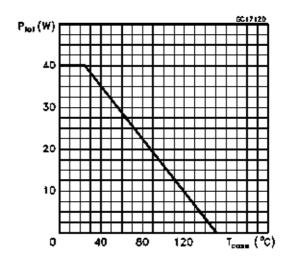
**Output Characteristics** 



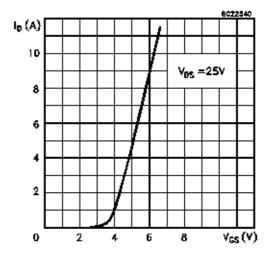
Thermal Impedance For ISOWATT220



Derating Curve For ISOWATT220



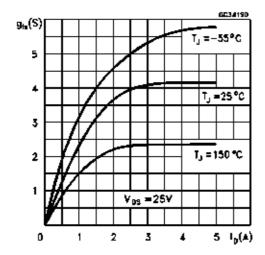
**Transfer Characteristics** 



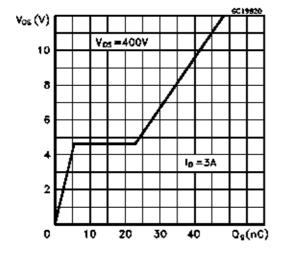
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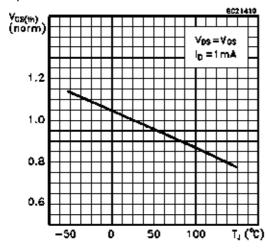
#### Transconductance



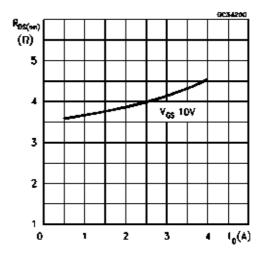
Gate Charge vs Gate-source Voltage



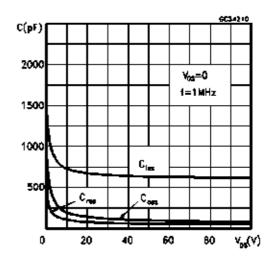
Normalized Gate Threshold Voltage vs Temperature



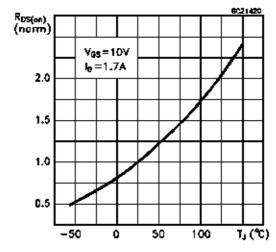
Static Drain-source On Resistance



Capacitance Variations

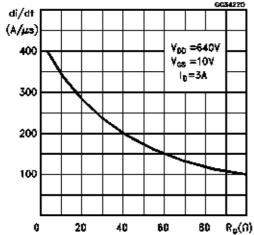


Normalized On Resistance vs Temperature

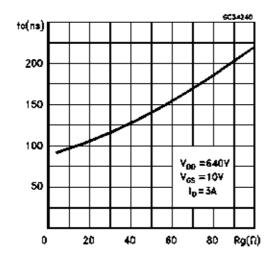




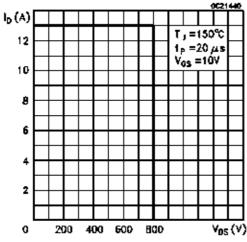
#### Turn-on Current Slope



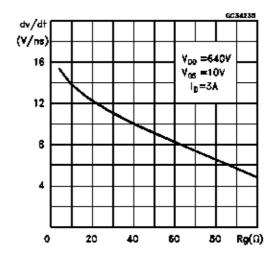
**Cross-over Time** 



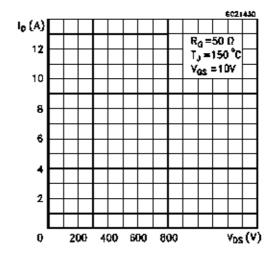
Accidental Overload Area



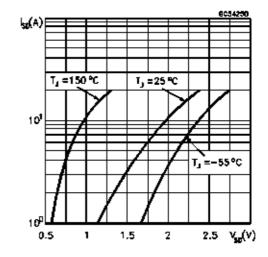
#### Turn-off Drain-source Voltage Slope



Switching Safe Operating Area



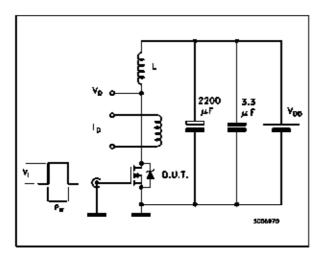
Source-drain Diode Forward Characteristics



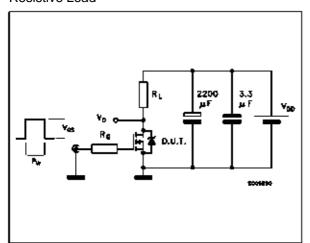
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Fig. 1: Unclamped Inductive Load Test Circuits



**Fig. 3:** Switching Times Test Circuits For Resistive Load



**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Reverse Recovery Time

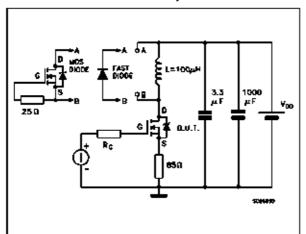


Fig. 2: Unclamped Inductive Waveforms

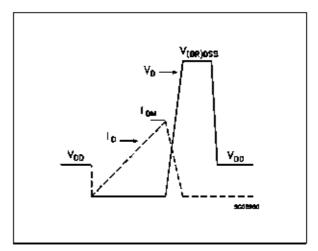
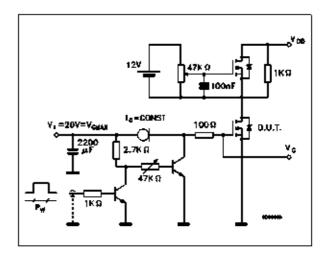
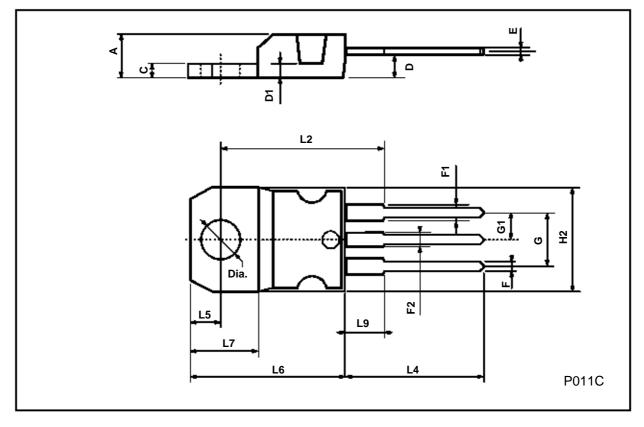


Fig. 4: Gate Charge Test Circuit



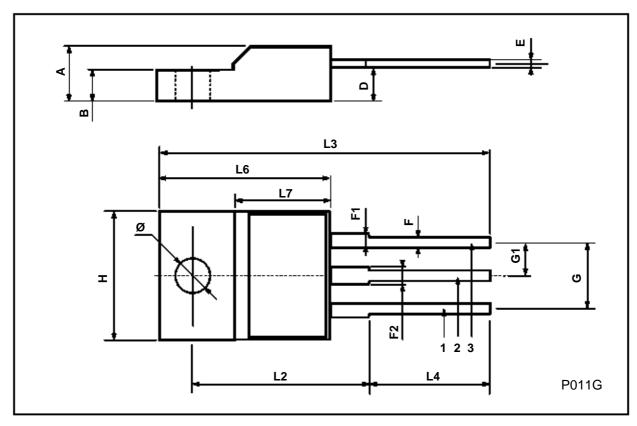
#### **TO-220 MECHANICAL DATA**

DIM.		mm			inch	
DIN.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
С	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
E	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.4		2.7	0.094		0.106
H2	10.0		10.40	0.393		0.409
L2		16.4			0.645	
L4	13.0		14.0	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.2		6.6	0.244		0.260
L9	3.5		3.93	0.137		0.154
DIA.	3.75		3.85	0.147		0.151



#### **ISOWATT220 MECHANICAL DATA**

DIM.		mm			inch	
DIW.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
Е	0.4		0.7	0.015		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.7	0.045		0.067
F2	1.15		1.7	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	0.385		0.417
L6	15.9	_	16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126



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